

E²SWITCH Project

Functional diversification with Tunnel FETs

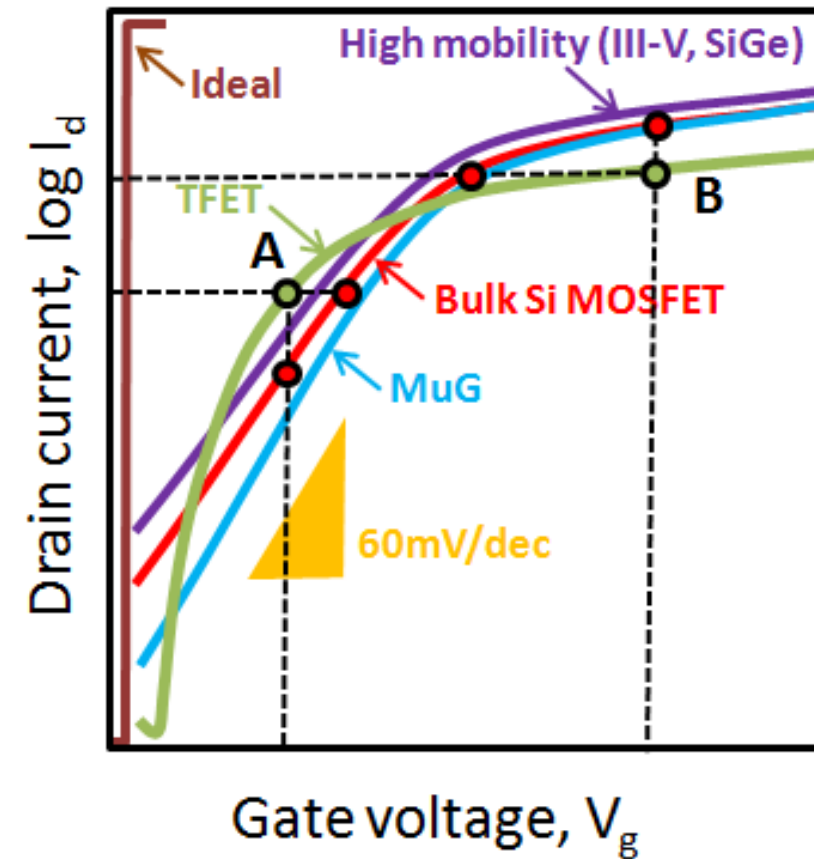
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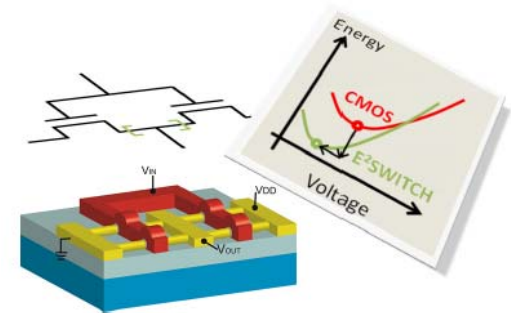
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E²SWITCH project

- Goals:
 - **Digital Tunnel FET**: operating at 0.25V with 10x better efficiency compared to nano-CMOS
 - **TFET fabrication** and technology optimization based on two advanced platforms
 - ✓ Complementary strained SiGe/Ge TFETs on silicon
 - ✓ Complementary III-V TFETs on silicon
 - **Analog Tunnel FET**: Exploration of new applications of Tunnel FETs in the field of analog/RF integrated circuits



E²SWITCH partners



No	Name	Short name	Country
1	ECOLE POLYTECHNIQUE FEDERALE DE LAUSANNE	EPFL	Switzerland
2	IBM RESEARCH GMBH	IBM	Switzerland
3	FORSCHUNGSZENTRUM JUELICH GMBH	JUELICH	Germany
4	LUNDS UNIVERSITET	LUND	Sweden
5	EIDGENOESSISCHE TECHNISCHE HOCHSCHULE ZURICH	ETHZ	Switzerland
6	INTERUNIVERSITAIR MICRO-ELECTRONICA CENTRUM VZW	IMEC	Belgium
7	CAMBRIDGE CMOS SENSORS LIMITED	CCS	United Kingdom
8	SCIPROM SARL	SCIPROM	Switzerland
9	CONSORZIO NAZIONALE INTERUNIVERSITARIO PER LA NANOELETTRONICA	IUNET	Italy

Analog Tunnel FET (1)

- Surface potential based **compact model** for all regimes of operation
- **Benchmarking** againsts 28nm FD SOI MOSFET (STMicroelectronics)

EPFL: compact DC & AC ambipolar model

$$\varphi_S(x) = \varphi_S^0 + (V_D - V_S + 2V_{BI}) \frac{\sinh(x/\lambda)}{\sinh(L_G/\lambda)} + \dots$$

$$(V_S - V_{BI} - \varphi_S^0) \frac{\sinh(x/\lambda) + \sinh(L_G - x)/\lambda}{\sinh(L_G/\lambda)} \quad (1)$$

$$E_G(T) = (A - B(T^2/(T + C))) \quad (2)$$

$$t_{src}(T) = \kappa_C[CB(hQf + 3U_t)] - \kappa_V[VB(hQf + 3U_t)] \quad (3)$$

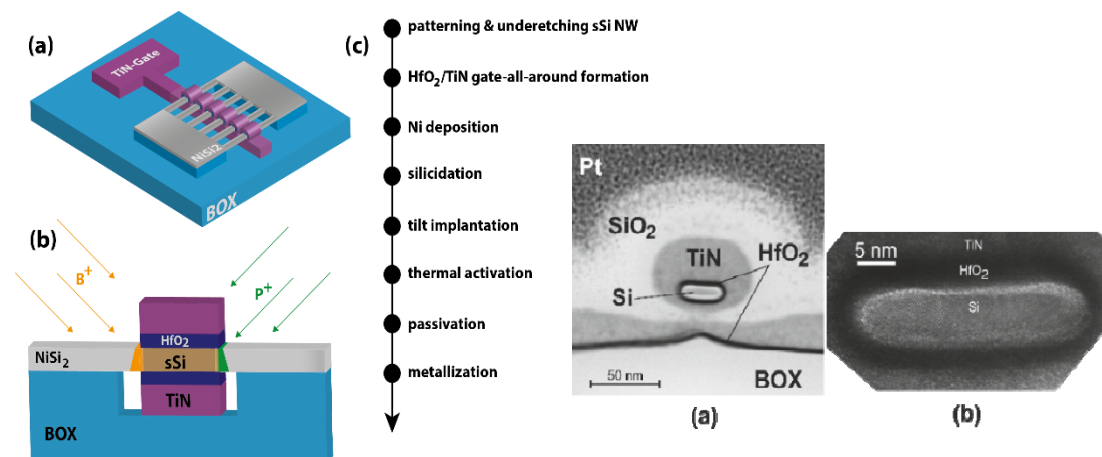
$$t_{drn}(T) = \kappa_C[CB(eQf - 3U_t)] - \kappa_V[VB(eQf - 3U_t)] \quad (4)$$

$$G_{src} = A_{pat} h(T) \left[\frac{E_G}{t_{src}} \right]^P \exp\left(\frac{-B_{pat} h(T) t_{src}}{E_G}\right) \quad (5)$$

$$G_{drn} = A_{pat} h(T) \left[\frac{E_G}{t_{drn}} \right]^P \exp\left(\frac{-B_{pat} h(T) t_{drn}}{E_G}\right) \quad (6)$$

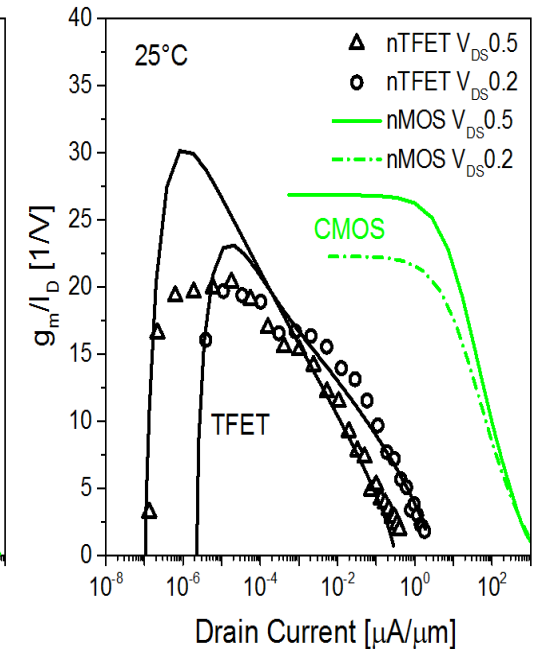
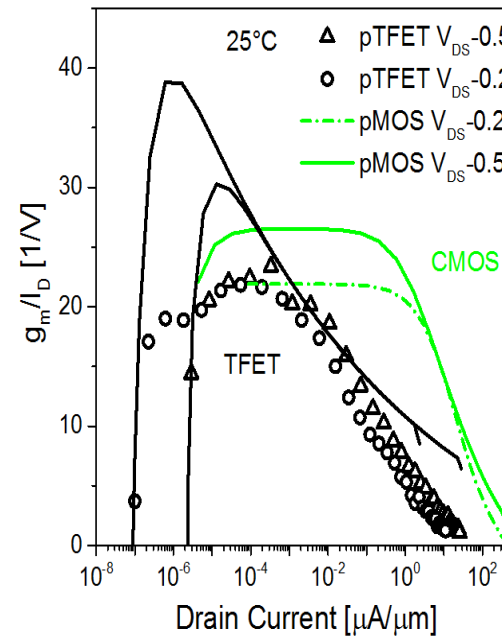
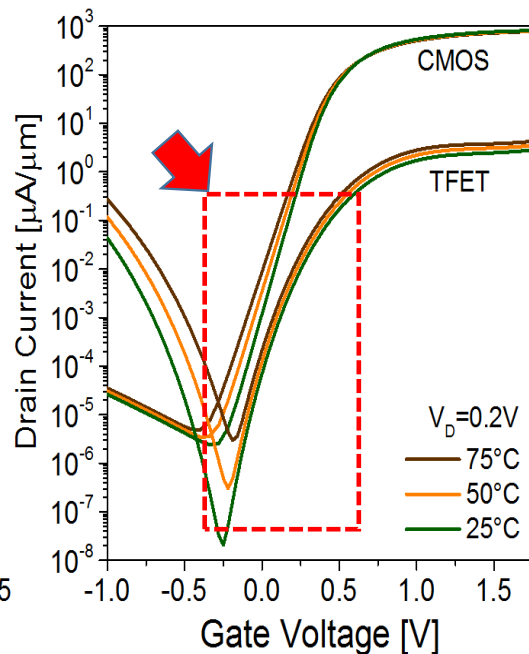
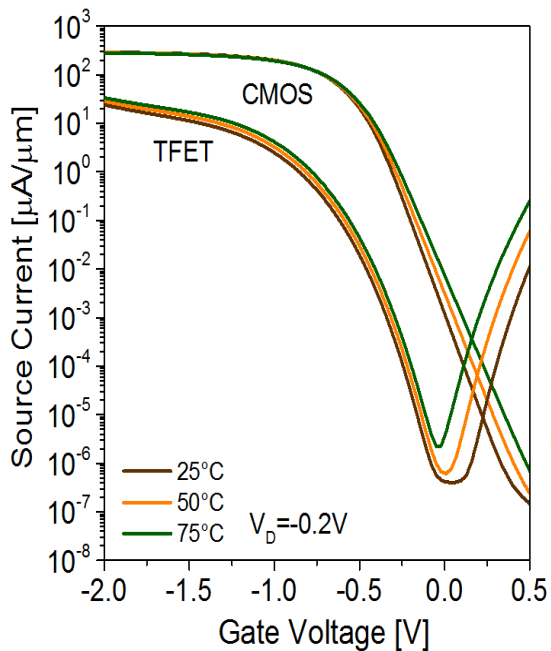
$$I_{tunn}(x, T) = qW_{ch} t_{ch} (G_{src} + G_{drn}) \quad (7)$$

Juelich: Complementary sSi Tunnel FETs



Analog Tunnel FET (2)

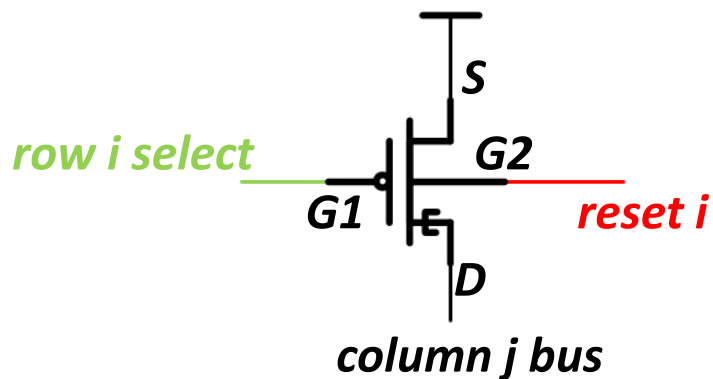
- 28nm Complementary Tunnel FETs versus FDSOI CMOS: benchmarking
- High analog gain and unity gain frequency per unit power for Tunnel FETs



1T APS with Tunnel FET

With 1 Tunnel FET:

- light-charge conversion
- charge storage
- pixel operations (reset, cell selection)
- in-pixel amplification

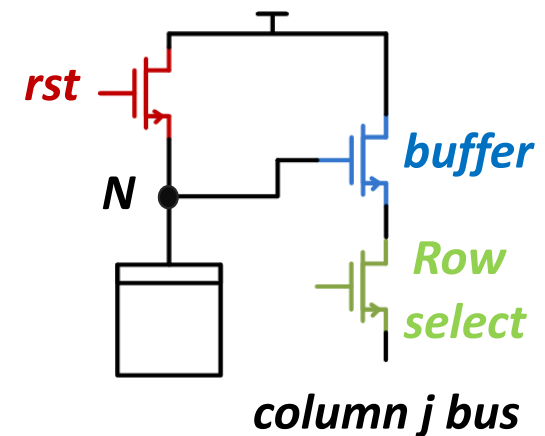


With CMOS:

Reset: **reset** is ON \rightarrow "N" is initialized

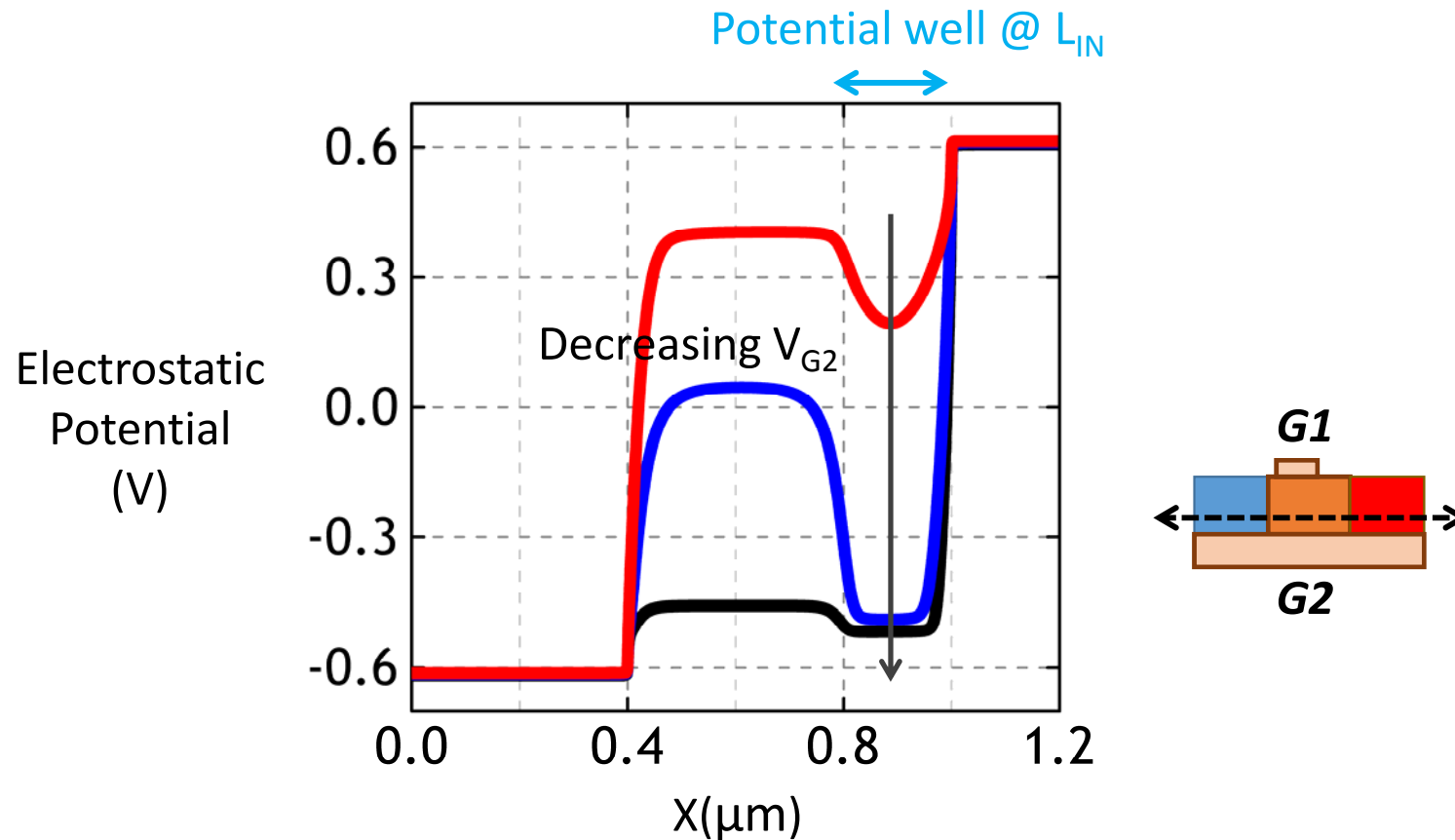
Integration: I_p discharges "N"

Read-out: **row select** is ON \rightarrow column select



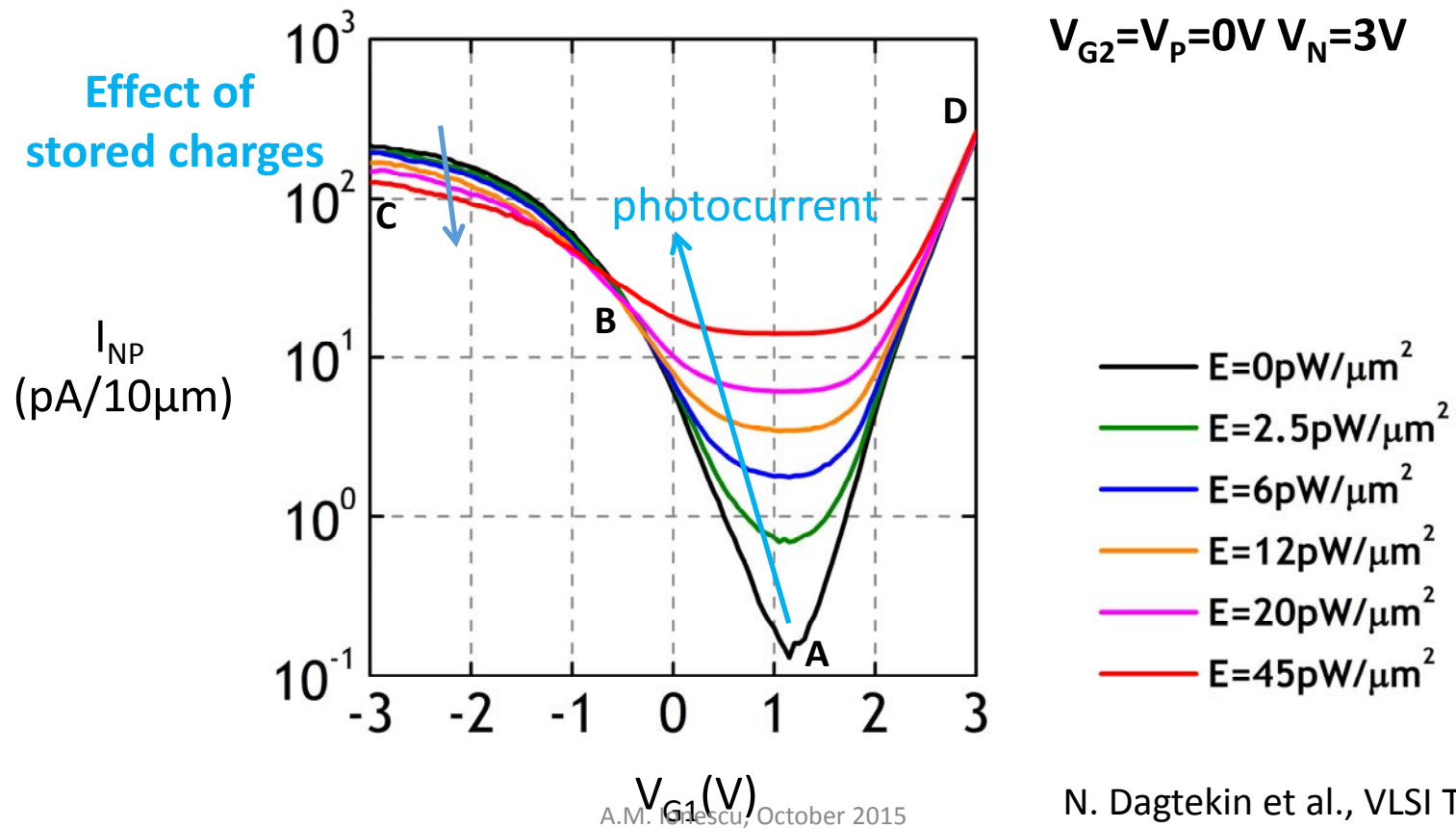
Tunnel FET with partial gate overlap

Charge storage, impact on tunneling current.



1 Tunnel FET APS

$I_{NP}-V_{G1}$ in all modes



A.M. Ionescu, October 2015

N. Dagtekin et al., VLSI Techn. Symp. 2015.

Functional diversification

- **Future analog and sensing functions with tunnel FETs**

- ✓ @ very low current & voltage
- ✓ analog gain @ very low current (sub-10nA)
- ✓ steep slope: higher sensitivity for bio and gas sensors. Selectivity?
- ✓ stability over larger temperature operation range
- ✓ New image sensors
- ✓ Energy efficient IoT applications